

IGBT³ Chip

Features:

- 600V Trench & Field Stop technology
- low V_{CE(sat)}
- low turn-off losses
- short tail current
- positive temperature coefficient
- easy paralleling

This chip is used for:

- power module
- discrete components

Applications:

drives



Chip Type	V _{CE}	<i>I</i> _C	Die Size	Package
SIGC28T60E	600V	50A	6.57 x 4.2 mm ²	sawn on foil

Mechanical Parameter

Raster size	6.57 x 4.2			
Emitter pad size (incl. gate pad)	2.166 x 3.401 2.432 x 3.401	mm ²		
Gate pad size	0.817 x 1.52			
Area total	27.6			
Thickness	70	μm		
Wafer size	200	mm		
Max.possible chips per wafer	974			
Passivation frontside	Photoimide			
Pad metal	3200 nm AlSiCu			
Backside metal	Ni Ag –system suitable for epoxy and soft solder die bonding			
Die bond	Electrically conductive glue or solder			
Wire bond	AI, <500μm			
Reject ink dot size	Ø 0.65mm ; max 1.2mm			
Recommended storage environment	Store in original container, in dry nitrogen, in dark environment, < 6 month at an ambient temperature of 23°C			



Maximum Ratings

Parameter	Symbol	Value	Unit	
Collector-Emitter voltage, T_{vj} =25 °C	V _{CE}	600	V	
DC collector current, limited by $T_{\rm vj\ max}$	I _C	1)	Α	
Pulsed collector current, $t_{\rm p}$ limited by $T_{\rm vj\;max}$	I _{c,puls}	150	Α	
Gate emitter voltage	V _{GE}	±20	V	
Junction temperature range	T _{vj}	-40 + 175	°C	
Operating junction temperature	T _{vj}	-40+150	°C	
Short circuit data 2) V_{GE} = 15V, V_{CC} = 360V, T_{vj} = 150°C	tsc	6	μs	
Reverse bias safe operating area ² (RBSOA)	$I_{C,max} = 100A, V_{CE,max} = 600V$ $T_{vj} \le 150^{\circ}C$			

¹⁾ depending on thermal properties of assembly

Static Characteristic (tested on wafer), T_{vj} =25 °C

Parameter	Symbol	Conditions	Value			Unit
- diamoto	- Cymison	Conditions	min.	typ.	max.	
Collector-Emitter breakdown voltage	V _{(BR)CES}	$V_{\rm GE}$ =0V , $I_{\rm C}$ = 4 mA	600			
Collector-Emitter saturation voltage	V _{CEsat}	V _{GE} =15V, I _C =50A	1.05	1.45	1.85	V
Gate-Emitter threshold voltage	$V_{GE(th)}$	$I_{\rm C}$ =0.8mA , $V_{\rm GE}$ = $V_{\rm CE}$	5.0	5.8	6.5	
Zero gate voltage collector current	I _{CES}	V _{CE} =600V , V _{GE} =0V			2.6	μA
Gate-Emitter leakage current	I _{GES}	V_{CE} =0V , V_{GE} =20V			600	nA
Integrated gate resistor	$r_{\rm G}$			none		Ω

Dynamic Characteristic (not subject to production test - verified by design / characterization), T_{vj} =25 °C

Parameter	Symbol	Conditions	Value			Unit
raiailietei	Syllibol	Conditions	min.	typ.	max.	Oilit
Input capacitance	Cies	V _{CE} =25V,		3140		
Output capacitance	Coes	V _{GE} =0V,		200		pF
Reverse transfer capacitance	C _{res}	<i>f</i> =1MHz		93		

²⁾ not subject to production test - verified by design/characterization



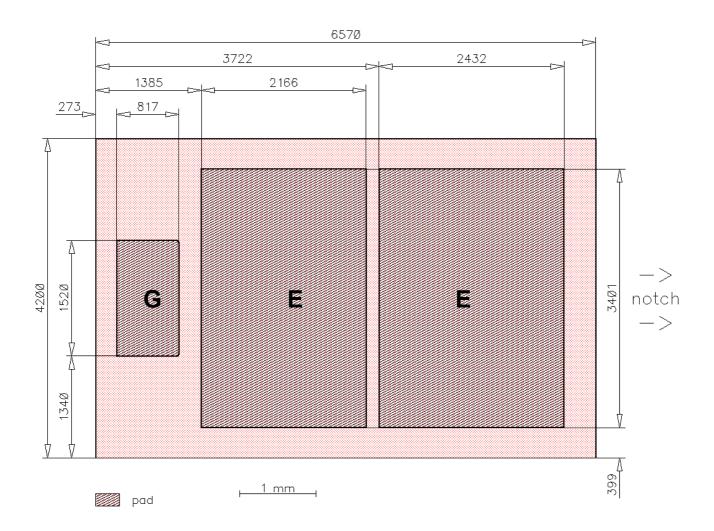
Further Electrical Characteristic

Switching characteristics and thermal properties are depending strongly on module design and mounting technology and can therefore not be specified for a bare die.



Chip Drawing

Die-Size 6570 um x 4200 um



E = Emitter pad

G = Gate pad



Description
AQL 0,65 for visual inspection according to failure catalogue
Electrostatic Discharge Sensitive Device according to MIL-STD 883

Revision History

Version	Subjects (major changes since last revision)	Date

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